

Description

The HXY50P03DF uses advanced trench technology

to provide excellent $R_{\text{DS}(\text{ON})},$ low gate charge and

operation with gate voltages as low as 4.5V. This

device is suitable for use as a

Battery protection or in other Switching application.

General Features

V_{DS} = -30V I_D =-50 A

 $R_{DS(ON)} < 13m\Omega @ V_{GS} = -10V$

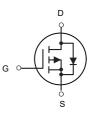
Application

Battery protection

Load switch Uninterruptible power supply







P-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
HXY50P03DF	DFN3X3-8L	50P03 XXX YYYY	5000

Absolute Maximum Ratings (TC=25°C unless otherwise specified)

		Rating		Units	
Symbol	Parameter	10s	Steady State	Units	
VDS	Drain-Source Voltage	-30		V	
VGS	Gate-Source Voltage	±	±20		
I _D @Tc=25℃	Continuous Drain Current, V _{GS} @ -10V ¹	-	-50		
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ -10V ¹	-	-27		
I _D @T _A =25℃	Continuous Drain Current, V _{GS} @ -10V ¹	-14.3	-9	А	
I _D @T _A =70°C	Continuous Drain Current, V _{GS} @ -10V ¹	-11.4	-7.2	А	
IDM	Pulsed Drain Current ²	-130		А	
EAS	Single Pulse Avalanche Energy ³	125		mJ	
IAS	Avalanche Current	-	-50		
P₀@Tc=25℃	Total Power Dissipation ⁴	37		W	
P₀@T _A =25°C	Total Power Dissipation ⁴	4.2	1.67	W	
TSTG	Storage Temperature Range	-55 to 150		°C	
TJ	Operating Junction Temperature Range	-55 to 150		°C	



HXY50P03DF

P-Channel Enhancement Mode MOSFET

R₀JA	Thermal Resistance Junction-Ambient ¹	75	°C/W
R₀JA	Thermal Resistance Junction-Ambient ¹ (t ≤10s)	30	°C/W
R₀JC	Thermal Resistance Junction-Case ¹	3.36	°C/W

Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-30			V
$\triangle BV$ DSS/ $\triangle T_J$	BVDSS Temperature Coefficient	Reference to 25°C , I _D =-1mA		-0.0232		V/°C
Rds(on)	Static Drain-Source On-Resistance ²	V _{GS} =-10V , I _D =-30A		9	13	mΩ
		V _{GS} =-4.5V , I _D =-15A		16	22	
$V_{GS(th)}$	Gate Threshold Voltage		-1.2		-2.5	V
$\bigtriangleup V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	$V_{GS}=V_{DS}$, I_D =-250uA		4.6		mV/°C
		V _{DS} =-24V , V _{GS} =0V , T _J =25°C			-1	
loss	Drain-Source Leakage Current	V _{DS} =-24V , V _{GS} =0V , T _J =55°C			-5	uA
lgss	Gate-Source Leakage Current	V_{GS} = $\pm20V$, V_{DS} = $0V$			±100	nA
gfs	Forward Transconductance	V _{DS} =-5V , I _D =-30A		30		S
Rg	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		9		Ω
Qg	Total Gate Charge (-4.5V)			22		
Qgs	Gate-Source Charge	──V _{DS} =-15V,V _{GS} =-4.5V,I _D =- 15A		8.7		nC
Qgd	Gate-Drain Charge			7.2		
Td(on)	Turn-On Delay Time			8		- ns
Tr	Rise Time	VDD=-15V , VGS=-10V ,		73.7		
Td(off)	Turn-Off Delay Time	—R _G =3.3 —I _D =-15A		61.8		
T _f	Fall Time	ID ISA		24.4		
Ciss	Input Capacitance			2215		
Coss	Output Capacitance	V _{DS} =-15V , V _{GS} =0V , f=1MHz		310		pF
Crss	Reverse Transfer Capacitance			237		
ls	Continuous Source Current ^{1,5}				-42	Α
lsм	Pulsed Source Current ^{2,5}	─V _G =V _D =0V , Force Current			-130	Α
Vsd	Diode Forward Voltage ²	V _{GS} =0V , I _S =-1A , T _J =25°C			-1	V
trr	Reverse Recovery Time	IF=-15A , dI/dt=100A/µs ,		19		nS
Qrr	Reverse Recovery Charge	TJ=25°C		9		nC

Note :

1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.

2.The data tested by pulsed , pulse width \leq 300us duty cycle \leq 2%

3. The EAS data shows Max. rating . The test condition is V_{DD} =-25V V_{GS} =-10V,L=0.1mH,I_{AS}=-50A,

4.The power dissipation is limited by 150°C junction temperature

5.The data is theoretically the same as $I_{\text{\tiny D}}$ and $I_{\text{\tiny DM}}$, in real applications , should be limited by total power dissipation.



Typical Characteristics

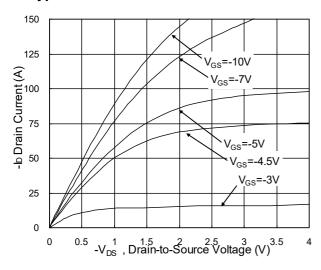


Fig.1 Typical Output Characteristics

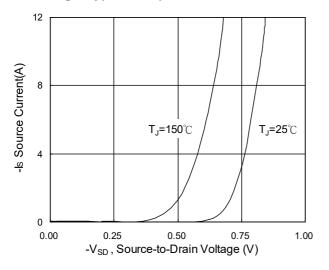
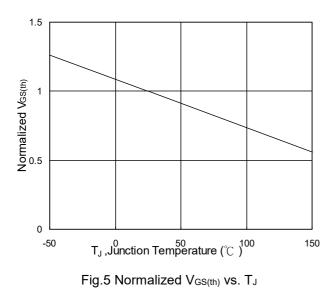


Fig.3 Forward Characteristics of Reverse



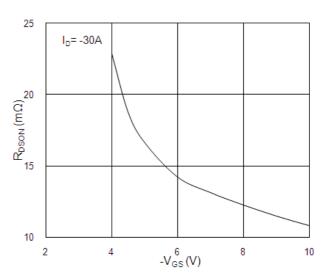


Fig.2 On-Resistance vs. G-S Voltage

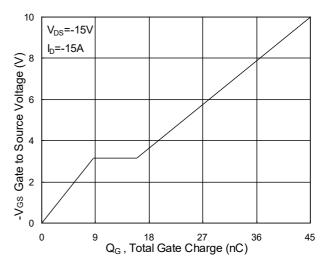


Fig.4 Gate-Charge Characteristics

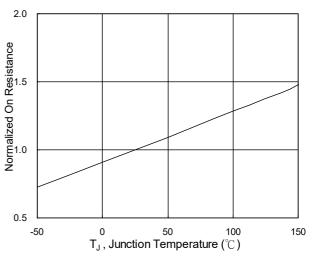


Fig.6 Normalized R_{DSON} vs. T_J



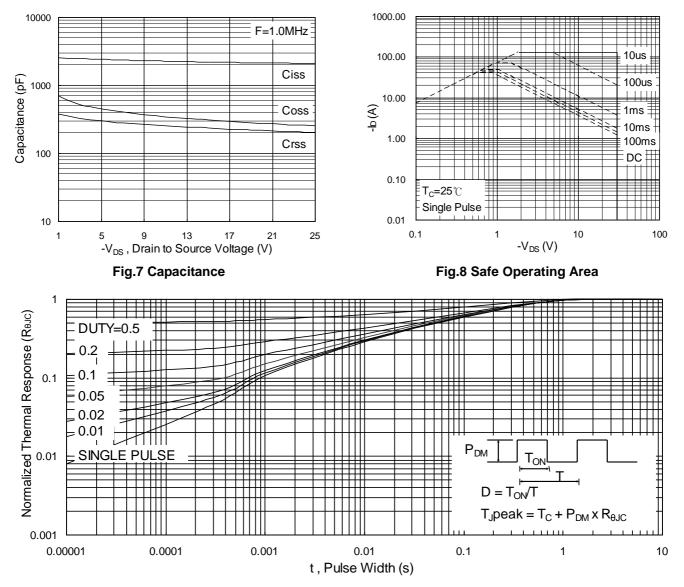


Fig.9 Normalized Maximum Transient Thermal Impedance

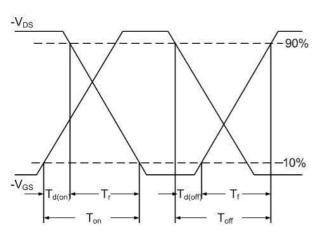


Fig.10 Switching Time Waveform

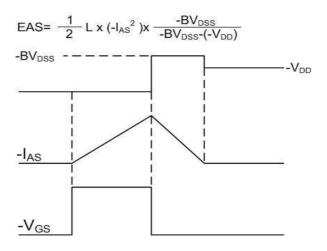
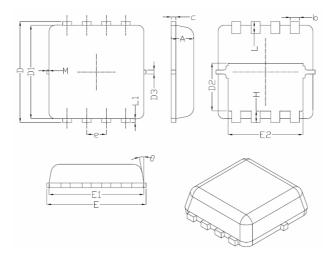


Fig.11 Unclamped Inductive Switching Waveform



DFN3X3-8L Package Information



Symphol	Dimensions In Millimeters			
Symbol	Min.	Nom.	Max.	
A	0.70	0.75	0.80	
b	0.25	0.30	0.35	
С	0.10	0.15	0.25	
D	3.25	3.35	3.45	
D1	3.00	3.10	3.20	
D2	1.48	1.58	1.68	
D3	-	0.13	-	
E	3.20	3.30	3.40	
E1	3.00	3.15	3.20	
E2	2.39	2.49	2.59	
e	0.65BSC			
Н	0.30	0.39	0.50	
L	0.30	0.40	0.50	
L1	-	0.13	-	
М	*	*	0.15	
θ		10 [°]	12 [°]	



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